

THE WORLD COMES HERE.
TMS2024
153rd Annual Meeting & Exhibition

MARCH 3–7, 2024
HYATT REGENCY ORLANDO
ORLANDO, FLORIDA, USA
#TMSAnnualMeeting



SUBMIT AN ABSTRACT FOR THE FOLLOWING TMS2024 SYMPOSIUM:

ADVANCED CHARACTERIZATION METHODS

Recent Advances in Electron Back-Scattered Diffraction and Related Techniques

This symposium focuses on the use of Electron Backscattered Diffraction (EBSD) in the Scanning Electron Microscope (SEM) but contributions on related SEM based techniques are encouraged as well including Transmission Kikuchi Diffraction (TKD), Electron Channeling Patterns (ECP) and Electron Channeling Contrast Imaging (ECCI).

We invite contributions in the following areas:

- Advances in theory, modeling, indexing and interpretation of diffraction patterns.
- Novel analysis and quantitative metrics of EBSD data
- Advances in detector systems, including direct electron detection.
- EBSD, TKD, and/or ECP/ECCI applications in Materials Science
- EBSD, TKD, and/or ECP/ECCI applications in Geology
- Open-source software related to EBSD, TKD, ECP, ECCI

ORGANIZERS

Stuart Wright, EDAX, USA
Marc De Graef, Carnegie Mellon University, USA
David Rowenhorst, Naval Research Laboratory, USA
Katharina Marquardt, Imperial College, United Kingdom

SYMPOSIUM SPONSORS

TMS Structural Materials Division
TMS Advanced Characterization, Testing, and Simulation Committee